


<b>Search Notes</b> 	<b>Application/Control No.</b> 10563617	<b>Applicant(s)/Patent Under Reexamination</b> NAKAMURA, NAOHITO
	<b>Examiner</b> M. Lee	<b>Art Unit</b> 2622

SEARCHED			
Class	Subclass	Date	Examiner
348	725, 726, 731, 732, 733	9/8/08	ml
375	329, 279, 326, 332	9/8/08	ml

SEARCH NOTES			
Search Notes		Date	Examiner
east		9/8/08	ml

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

	/M. Lee/ Primary Examiner.Art Unit 2622
--	--